

Lecture 16 : Sensitivity, SFDR, MOSFET 2-port noise parameters

* Sensitivity \equiv minimum signal power level that can be detected with desired SNR

Recall that available noise power = kTB Watts

$$\Rightarrow SNR_{in} = \frac{P_{sig}}{kTB}, \text{ where } P_{sig} = \text{received signal power}$$

we want to determine $P_{sig,min}$ for a desired $SNR_{out,min}$.

$$F = \frac{SNR_{in}}{SNR_{out}}$$
$$= \frac{P_{sig}/kTB}{SNR_{out}}$$

$$\Rightarrow P_{sig} = (kTB) \cdot (SNR_{out}) \cdot (F)$$

expressed in decibels (dBm or dB)

$$P_{in,min}/dBm = 10 \log(kT) + NF/dB + SNR_{min}/dB$$
$$+ 10 \log B$$

$$@ T = 300K, 10 \log kT = -174 \text{ dBm/Hz}$$

$$P_{in,min} = \underbrace{-174 \text{ dBm/Hz} + NF + 10 \log B}_{= \text{noise floor}} + SNR_{min}.$$

* $P_{in,min}$ is a function of BW

→ a receiver with narrowband channel may appear to be sensitive compared to another with a wide channel

Dynamic Range:

$$DR \equiv \frac{\text{max input level tolerated}}{\text{min. input level meeting SNR requirements}}$$

However in RF design

* Distortion is defined differently (IIP3)

* input signal must provide SNR_{min} .

Spurious Free Dynamic Range = SFDR

→ upper end defined by IM behaviour

→ lower end defined by sensitivity

* upper end = max input level for which IM3 products in a two-tone test do not exceed the noise floor.

Recall that

$$\begin{aligned} P_{IIP3} &= P_{in} + \frac{P_{out} - P_{IM,out}}{2} \\ &= P_{in} + \frac{P_{in} - P_{IM,in}}{2} \quad \left\{ \begin{array}{l} P_{out} = P_{in} + G_{dB} \\ P_{IM,out} = P_{IM,in} + G_{dB} \end{array} \right\} \\ &= \frac{3P_{in} - P_{IM,in}}{2} \end{aligned}$$

$$\Rightarrow P_{in} = \frac{2P_{1IP_3} + P_{IM, in}}{3}$$

$$NFL = -174 + NF + 10 \log B$$

$$\therefore P_{in, max} = \frac{2P_{1IP_3} + NFL}{3}$$

$$P_{in, min.} = NFL + SNR_{min.}$$

$$\Rightarrow SFDR = P_{in, max} - P_{in, min.}$$

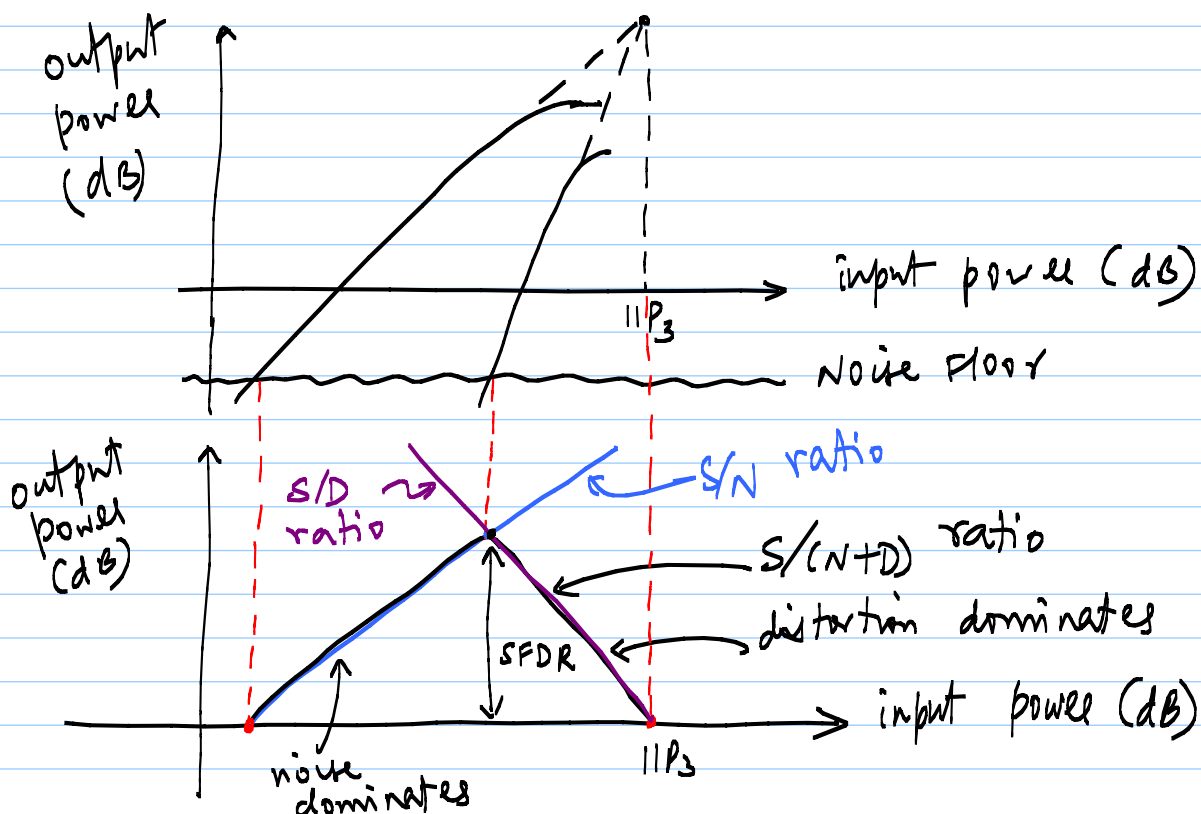
$$= \frac{2P_{1IP_3} + NFL}{3} - (NFL + SNR_{min.})$$

$$= \frac{2(P_{1IP_3} - NFL)}{3} - SNR_{min.} //$$

e.g. Consider a receiver with $NF = 9 \text{ dB}$,

$P_{1IP_3} = -15 \text{ dBm}$, $B = 200 \text{ kHz}$, $SNR_{min} = 12 \text{ dB}$

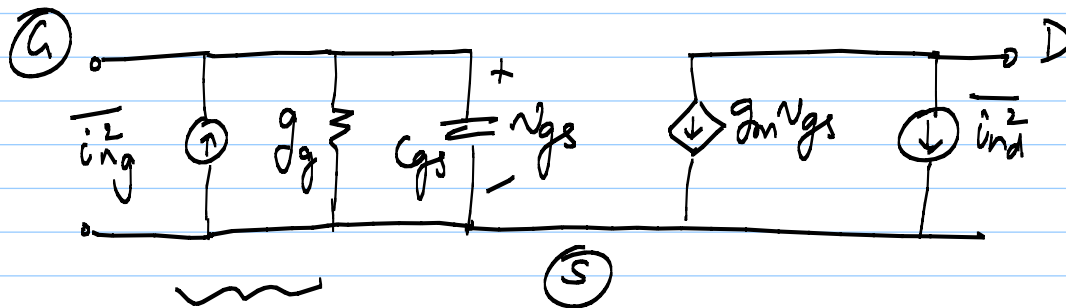
$$\Rightarrow SFDR \approx 53 \text{ dB}$$



MOSFET 2-port noise parameters:

→ brief description only

→ for complete treatment, please refer to Section 11.2 in Thomas Lee's textbook



from van der Ziel

* Recall,

$$\overline{i_{nd}^2} = 4kT \delta g_d \Delta f$$
$$\overline{i_{ng}^2} = 4kT \delta g_g \Delta f$$
$$g_g = \omega^2 C_{gs}^2 / 5g_d$$

* also recall that gate & drain noise are correlated

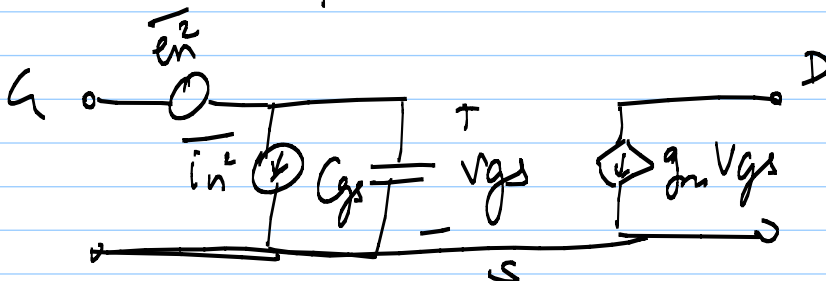
correlation coefficient $C \equiv \frac{\overline{i_{ng} \cdot i_{nd}^*}}{\sqrt{\overline{i_{ng}^2}} \sqrt{\overline{i_{nd}^2}}}$

* for a long channel MOSFET, $C = j0.395$

→ assume true for short channel also

* 2-port noise parameters are

$$R_N = \frac{\overline{e_n^2}}{4kT\Delta f} ; G_n = \frac{\overline{i_n^2}}{4kT\Delta f} ; Y_c = G_c + jB_c = \frac{\overline{i_c}}{\overline{e_n}}$$



1) input is shorted \Rightarrow gate noise does not go to o/p

$$\text{ckt} \Rightarrow V_{gs} = 0, \overline{i_{out}^2} = \overline{i_{nd}^2}$$

$$2\text{-port} \Rightarrow V_{gs} = \overline{e_n} \Rightarrow \overline{i_{out}^2} = g_m^2 \overline{e_n^2}$$

equating:

$$\overline{e_n^2} = \frac{\overline{i_{nd}^2}}{g_m^2}$$

$$\Rightarrow R_N = \frac{\overline{e_n^2}}{4kT\Delta f} = \frac{\gamma g_{do}}{g_m^2} = \frac{\gamma}{\alpha g_m} //$$

$$\alpha \equiv \frac{g_m}{g_{do}}$$

2) Input is open ckt:

$$a) \overline{i_d^2} \text{ only} : \overline{i_n^2} = \frac{\overline{i_{nd}^2} \cdot (j\omega C_{gs})^2}{g_m^2} = \overline{e_n^2} \cdot (j\omega C_{gs})^2$$

$\Rightarrow \overline{i_n}$ is completely correlated with $\overline{e_n}$

b) $\overline{i_{ng}} + \overline{i_{nd}}$

$$\text{let } \overline{i_{ng}} = \underbrace{\overline{i_{ngc}}}_{\text{correlated with } \overline{e_n}} + \underbrace{\overline{i_{ngn}}}_{\text{uncorrelated with } \overline{e_n}}$$

$$\Rightarrow Y_c = \frac{\overline{i_{ni}} + \overline{i_{ngc}}}{\overline{e_n}} = j\omega C_{gs} + \frac{\overline{i_{ngc}}}{\overline{e_n}}$$

$$= j\omega C_{gs} + g_m \frac{\overline{i_{ngc}}}{\overline{i_{nd}}}$$

$$= j\omega C_{gs} + g_m \frac{\overline{i_{ngc} \cdot i_{nd}^*}}{\overline{i_{nd} \cdot i_{nd}^*}}$$

{ multiply and
divide by $\overline{i_{nd}^*}$ }

$$= j\omega C_{gs} + g_m \frac{\overline{i_{ngc} \cdot i_{nd}^*}}{\sqrt{\overline{i_{nd}^2}} \cdot \sqrt{\overline{i_{nd}^2}}}$$

$$= j\omega C_{gs} + g_m \cdot \frac{\overline{i_{ngc} i_{nd}^*}}{\sqrt{i_{nd}^2} \sqrt{i_{nd}^2}} \cdot \frac{\sqrt{i_{ng}^2}}{\sqrt{i_{ng}^2}}$$

= C
correlation
coefft.

$$= j\omega C_{gs} + g_m \cdot C \cdot \sqrt{\frac{i_{ng}^2}{i_{nd}^2}} \quad \left\{ \begin{array}{l} C = \text{correlation} \\ \text{coefficient} \end{array} \right\}$$

$$= j\omega C_{gs} + j g_m |c| \sqrt{\frac{g_{gs}}{g_{ds}}} \quad \left\{ \begin{array}{l} C = j 0.395 \\ \text{ideally} \end{array} \right\}$$

$$Y_c = j\omega C_{gs} \left\{ 1 + \frac{g_m}{g_{ds}} |c| \sqrt{\frac{g_{gs}}{g_{ds}}} \right\}$$

$$\Rightarrow Y_c = j\omega C_{gs} \left\{ 1 + \alpha |c| \sqrt{\frac{g_{gs}}{g_{ds}}} \right\}$$

$$Y_c = G_c + j B_c$$

$$\Rightarrow \left\{ \begin{array}{l} G_c = 0 \\ B_c = \omega C_{gs} \left(1 + \alpha |c| \sqrt{\frac{g_{gs}}{g_{ds}}} \right) \end{array} \right.$$

→ $G_c = 0$ ∵ we have neglected gate resistance

→ $Y_c \neq j\omega C_{gs}$ (condition for max power transfer)
i.e. min. noise condition is different from
max power

$$\begin{aligned}
 3) \quad \overline{i_{ng}^2} &= \overline{(i_{ngc} + i_{ngu})^2} = \overline{i_{ngc}^2} + \overline{i_{ngu}^2} \\
 &= \underbrace{4kT \delta g_g \Delta f |c|^2}_{\overline{i_{ngc}^2}} + \underbrace{4kT \delta g_g \Delta f (1-|c|^2)}_{\overline{i_{ngu}^2}}
 \end{aligned}$$

$$G_u = \frac{\overline{i_{ngw}^2}}{4kT \Delta f}$$

$$\Rightarrow \boxed{G_u = \frac{\delta \omega^2 (g_s^2 (1-|c|^2))}{5 g_{do}}}$$

$$* \quad B_{opt} = -B_c = -\omega (g_s (1 + \alpha |c| \sqrt{\frac{\delta}{5\gamma}}))$$

→ inductive in character

→ wrong frequency behaviour ($\propto \omega$ instead of $\propto \frac{1}{\omega}$) \Rightarrow broadband noise match is fundamentally difficult

$$* \quad G_{opt} = \sqrt{\frac{G_u}{R_N} - G_c^2} = \alpha \omega g_s \sqrt{\frac{\delta}{5\gamma} (1-|c|^2)}$$

$$* \quad F_{min.} = 1 + 2 R_N [G_{opt} + G_c]$$

$$\Rightarrow F_{min.} \approx 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_T} \sqrt{2\delta (1-|c|^2)}$$

→ Faster devices yield lower noise at given ω

→ e.g. $\gamma = 2$, $\delta = 4$

ω_T / ω	$F_{min} (dB)$
20	0.5
15	0.6
10	0.9
5	1.6

→ F_{min} assumes no constraint on power